APPENDIX

3. A method as claimed in claim 1~~ or 2~~, where the grid structure is an X-ray scatter grid with successive regions having different X-ray absorption coefficients, characterized in that material strips exhibiting a different X-ray absorption behavior are used.

6. An examination apparatus (1) for irradiating an object (4) by means of X-rays (3), the examination apparatus (1) including an X-ray source (2), an X-ray detector (8), a receiving space (5) for the object (4) to be irradiated, arranged between the X-ray source (2) and the X-ray detector (8) and an X-ray scatter grid (6) with successive regions of different X-ray absorptivity (3), said X-ray scatter grid to be arranged between the object (4) and the X-ray detector (8), characterized in that said X-ray scatter grid is manufactured according to ~~one of the preceding claims 3 to 5~~claim 3.